

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/922,183	JINDA ET AL.	
Examiner	Art Unit	
Tom V. Sheng	2673	

SEARCHED					
Class	Subclass	Date	Examiner		
345°	87-89 94	b/relat	75		
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	210				
	MET				
	620				
	691				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
Ahroe	Starled	6/2/et	75		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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See att, note				
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